

N-channel 600 V, 0.71 Ω typ., 5.5 A MDmesh™ M2 Power MOSFET in a TO-220FP package

Datasheet - production data

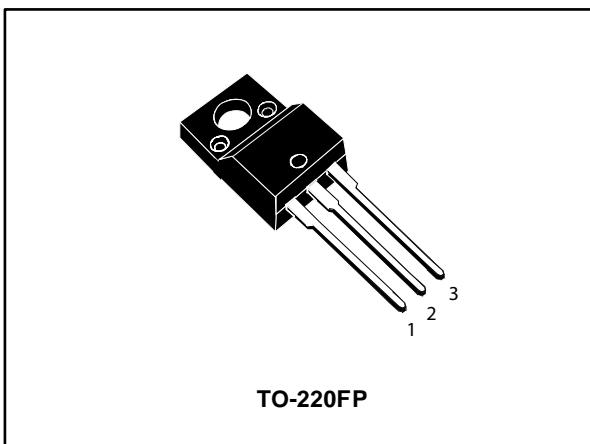
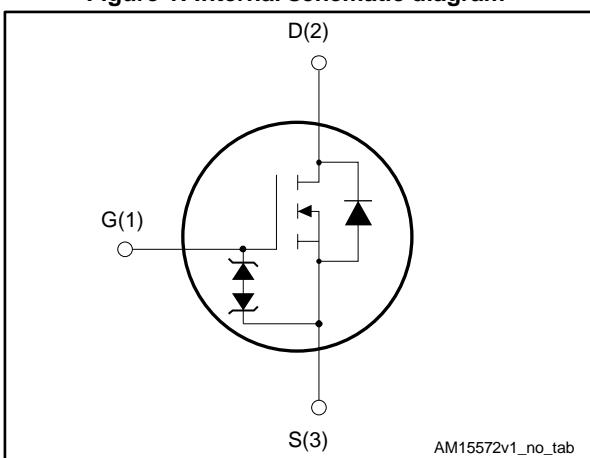


Figure 1: Internal schematic diagram



Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|------------|-----------------|--------------------------|----------------|
| STF9HN65M2 | 600 V | 0.82 Ω | 5.5 A |

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

| Order code | Marking | Package | Packing |
|------------|---------|----------|---------|
| STF9HN65M2 | 9HN65M2 | TO-220FP | Tube |

Contents

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1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|-------------|------------------|
| V_{GS} | Gate-source voltage | ± 25 | V |
| $I_D^{(1)}$ | Drain current (continuous) at $T_C = 25^\circ\text{C}$ | 5.5 | A |
| $I_D^{(1)}$ | Drain current (continuous) at $T_C = 100^\circ\text{C}$ | 3.5 | A |
| $I_{DM}^{(2)}$ | Drain current (pulsed) | 22 | A |
| P_{TOT} | Total dissipation at $T_C = 25^\circ\text{C}$ | 20 | W |
| $dv/dt^{(3)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(4)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| V_{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1\text{ s}$, $T_C = 25^\circ\text{C}$) | 2500 | V_{ISO} |
| T_{stg} | Storage temperature | - 55 to 150 | $^\circ\text{C}$ |
| T_j | Max. operating junction temperature | 150 | |

Notes:

- (1) Limited only by maximum temperature allowed.
- (2) Pulse width limited by safe operating area.
- (3) $I_{SD} \leq 5.5\text{ A}$, $dI/dt \leq 400\text{ A}/\mu\text{s}$; V_{DS} peak < $V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$.
- (4) $V_{DS} \leq 520\text{ V}$.

Table 3: Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|--|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max. | 6.25 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient max. | 62.5 | $^\circ\text{C}/\text{W}$ |

Table 4: Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax}) | 1.0 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$) | 105 | mJ |

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified).

Table 5: Static

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|-----------------------------------|---|------|------|----------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage | $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$ | 650 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$ | | | 1 | μA |
| | | $V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$ | | | 100 | μA |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$ | | | ± 10 | μA |
| $V_{GS(\text{th})}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$ | 2 | 3 | 4 | V |
| $R_{DS(\text{on})}$ | Static drain-source on-resistance | $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$ | | 0.71 | 0.82 | Ω |

Table 6: Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|-------------------------------|--|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$ | - | 325 | - | pF |
| C_{oss} | Output capacitance | | - | 16 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 0.85 | - | pF |
| $C_{oss \text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{DS} = 0 \text{ V to } 520 \text{ V}, V_{GS} = 0 \text{ V}$ | - | 109 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1 \text{ MHz}$ open drain | - | 5.6 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 520 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$ (see Figure 15: "Gate charge test circuit") | - | 11.5 | - | nC |
| Q_{gs} | Gate-source charge | | - | 2.5 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 5 | - | nC |

Notes:

⁽¹⁾ $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 7: Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 325 \text{ V}, I_D = 2.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 14: "Switching times test circuit for resistive load" and Figure 19: "Switching time waveform") | - | 7.5 | - | ns |
| t_r | Rise time | | - | 4.6 | - | ns |
| $t_{d(off)}$ | Turn-off-delay time | | - | 24 | - | ns |
| t_f | Fall time | | - | 14.5 | - | ns |

Table 8: Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|--|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 5.5 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 22 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $V_{GS} = 0 \text{ V}, I_{SD} = 5 \text{ A}$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}$ (see Figure 16: "Test circuit for inductive load switching and diode recovery times") | - | 268 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 1.7 | | μC |
| I_{RRM} | Reverse recovery current | | - | 12.5 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}, T_j = 150 \text{ }^\circ\text{C}$ (see Figure 16: "Test circuit for inductive load switching and diode recovery times") | - | 408 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 2.6 | | μC |
| I_{RRM} | Reverse recovery current | | - | 13 | | A |

Notes:

(1) Pulse width is limited by safe operating area.

(2) Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

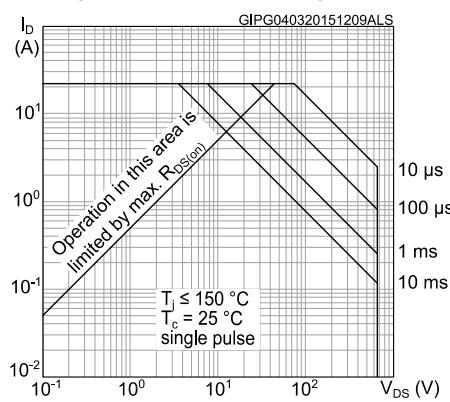
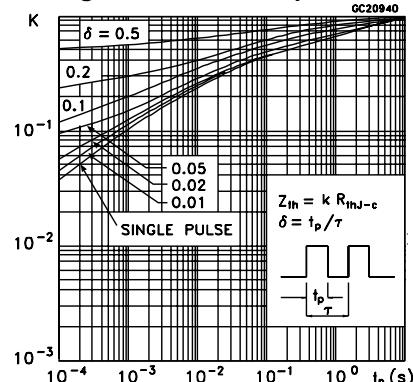
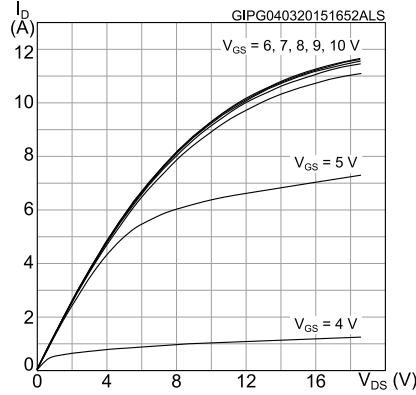
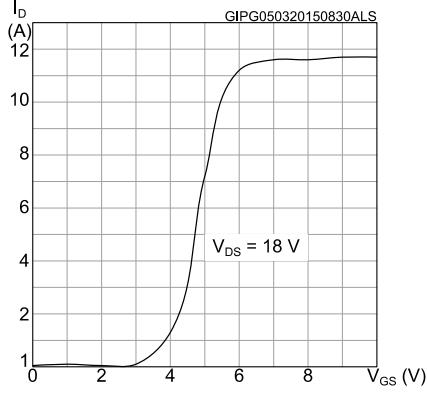
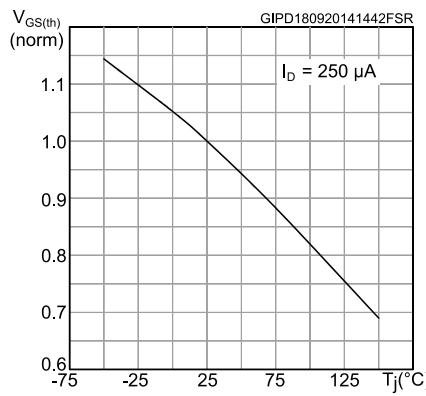
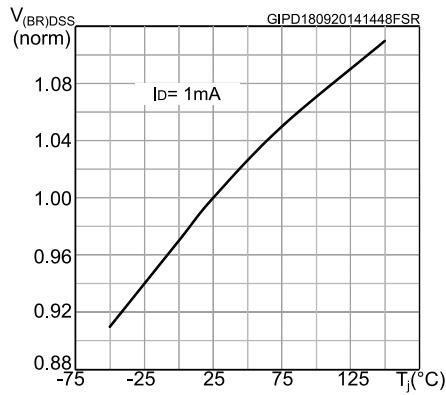
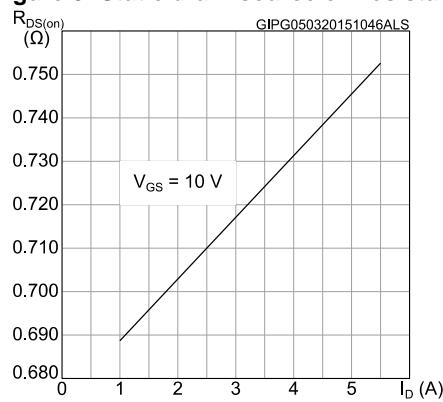
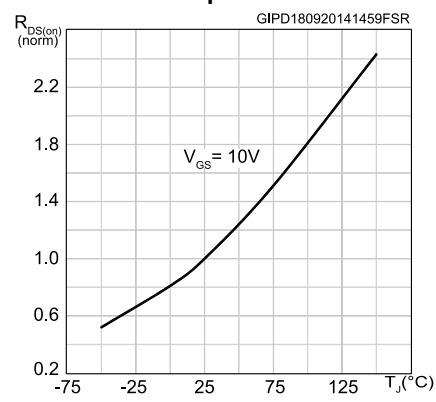
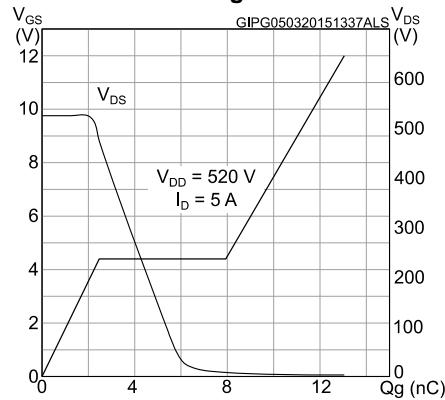
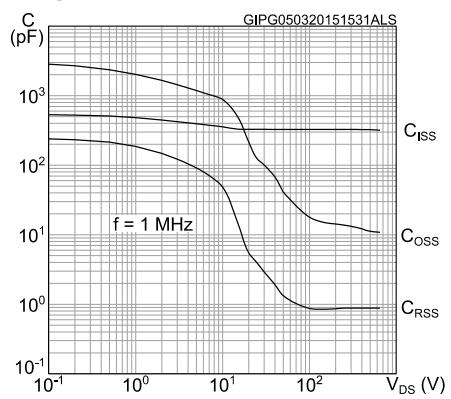
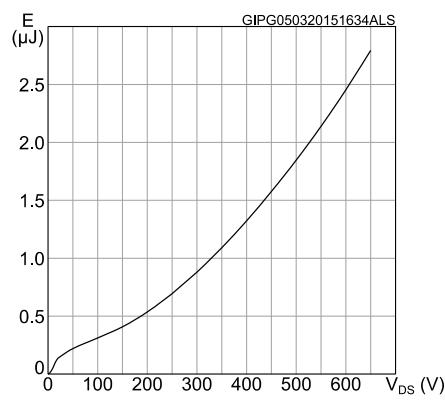
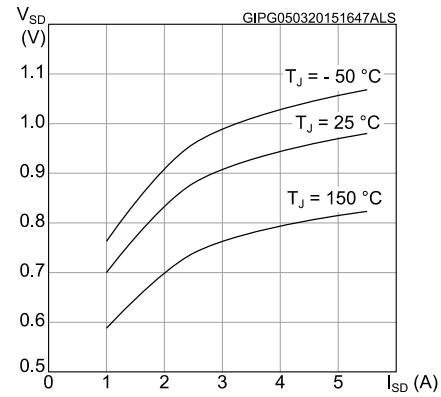
Figure 2: Safe operating area**Figure 3: Thermal impedance****Figure 4: Output characteristics****Figure 5: Transfer characteristics****Figure 6: Normalized gate threshold voltage vs. temperature****Figure 7: Normalized V(BR)DSS vs. temperature**

Figure 8: Static drain-source on-resistance**Figure 9: Normalized on-resistance vs. temperature****Figure 10: Gate charge vs. gate-source voltage****Figure 11: Capacitance variations****Figure 12: Output capacitance stored energy****Figure 13: Source-drain diode forward characteristics**

3 Test circuits

Figure 14: Switching times test circuit for resistive load

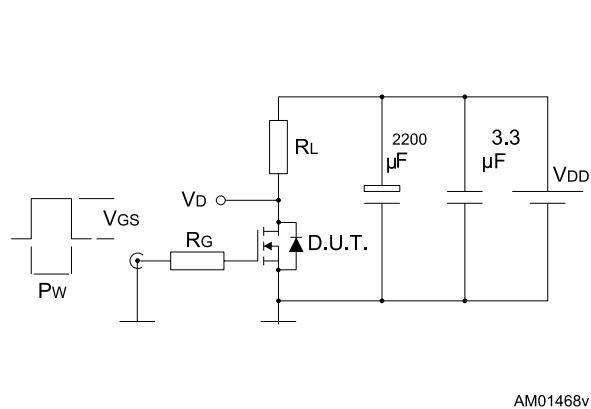


Figure 15: Gate charge test circuit

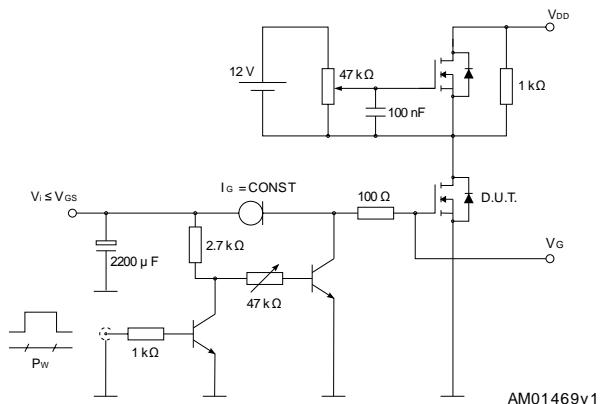


Figure 16: Test circuit for inductive load switching and diode recovery times

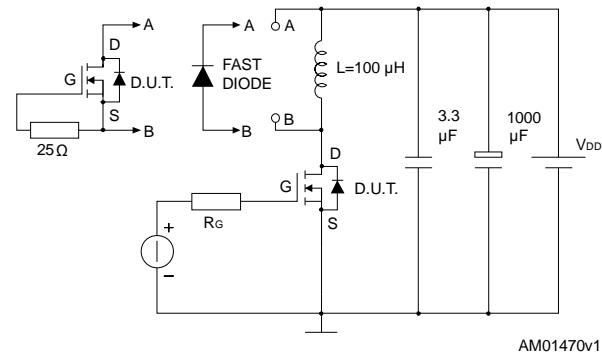


Figure 17: Unclamped inductive load test circuit

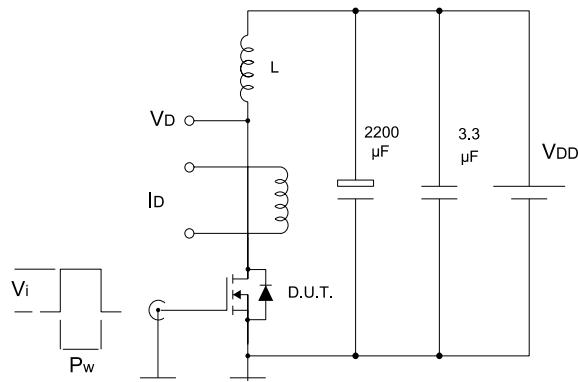


Figure 18: Unclamped inductive waveform

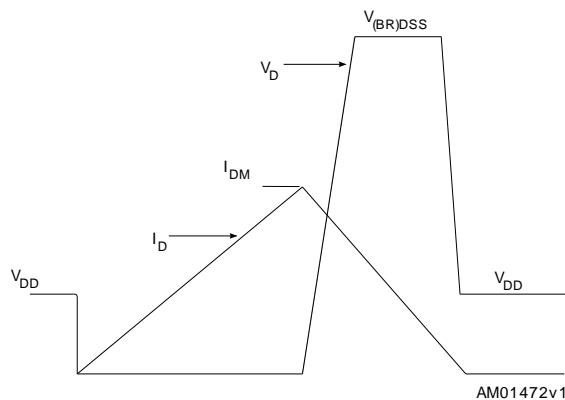
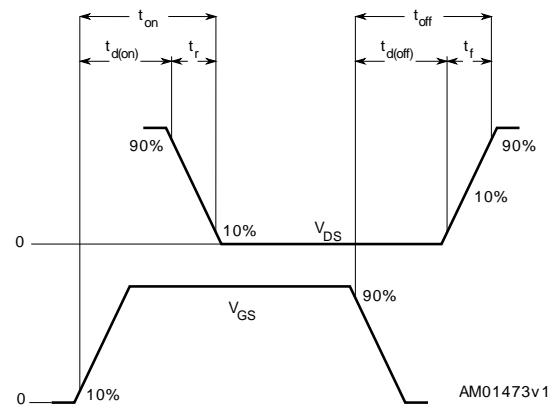


Figure 19: Switching time waveform

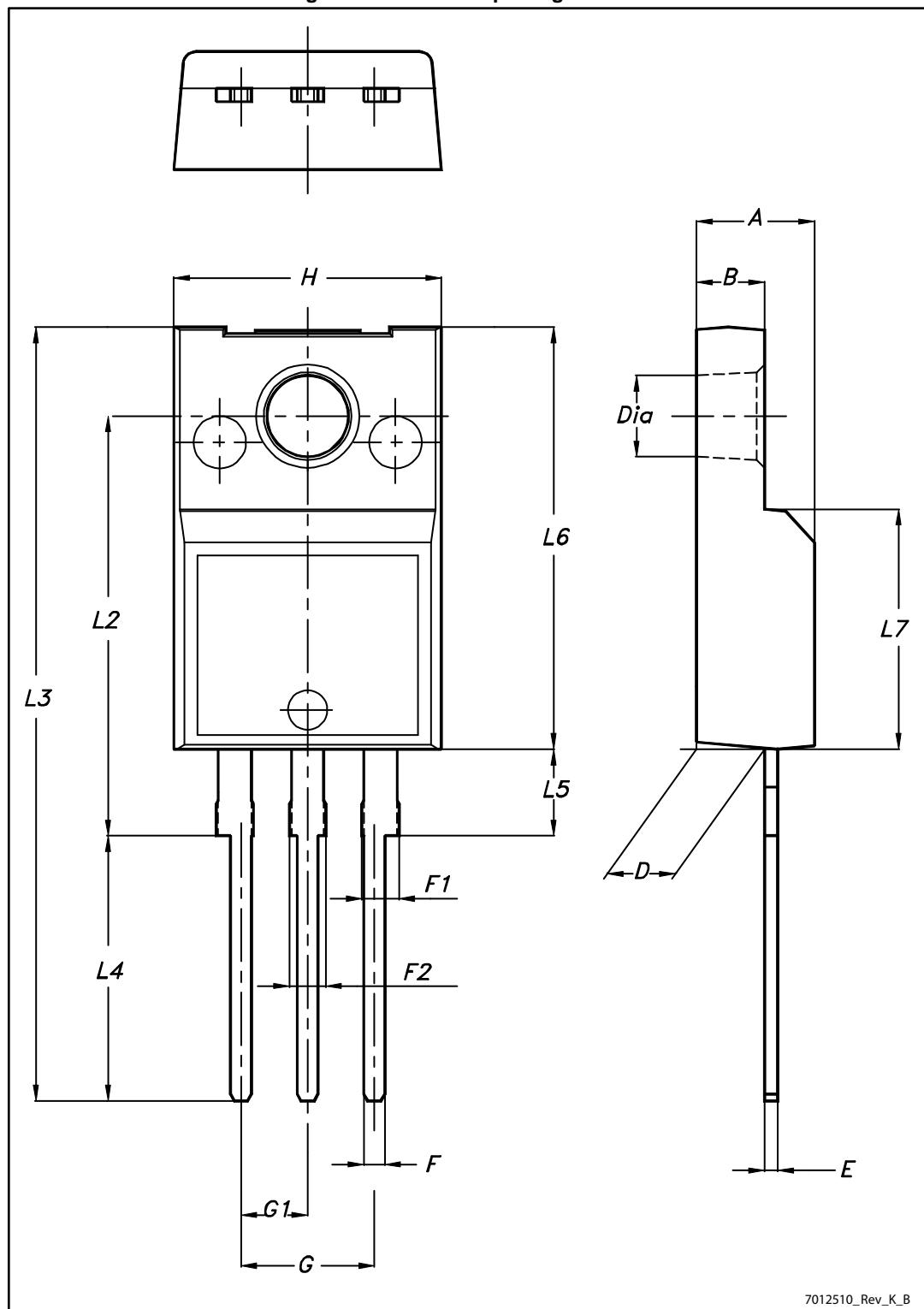


4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

4.1 TO-220FP package information

Figure 20: TO-220FP package outline



7012510_Rev_K_B

Table 9: TO-220FP mechanical data

| Dim. | mm | | |
|------|------|------|------|
| | Min. | Typ. | Max. |
| A | 4.4 | | 4.6 |
| B | 2.5 | | 2.7 |
| D | 2.5 | | 2.75 |
| E | 0.45 | | 0.7 |
| F | 0.75 | | 1 |
| F1 | 1.15 | | 1.70 |
| F2 | 1.15 | | 1.70 |
| G | 4.95 | | 5.2 |
| G1 | 2.4 | | 2.7 |
| H | 10 | | 10.4 |
| L2 | | 16 | |
| L3 | 28.6 | | 30.6 |
| L4 | 9.8 | | 10.6 |
| L5 | 2.9 | | 3.6 |
| L6 | 15.9 | | 16.4 |
| L7 | 9 | | 9.3 |
| Dia | 3 | | 3.2 |

5 Revision history

Table 10: Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 11-Mar-2015 | 1 | Initial release. |
| 23-Apr-2015 | 2 | Document status promoted to 'Production data'. |

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